Application/Control No.

10/533,860

Examiner

Jason M. Perilla

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Page 1 of 6

## **U.S. PATENT DOCUMENTS**

*		Document Number Date Country Code-Number-Kind Code MM-YYYY Name	Name	Classification	
*	Α	US-4,291,277 A	09-1981	Davis et al.	330/149
*	В	US-4,700,151 A	10-1987	Nagata, Yoshinori	332/123
*	С	US-5,049,832 A	09-1991	Cavers, James K.	330/149
*	D	US-5,148,448 A	09-1992	Karam et al.	375/298
*	Е	US-5,507,014 A	04-1996	Wray et al.	455/114.3
*	F	US-5,559,807 A	09-1996	van den Heuvel et al.	370/347
*	G	US-5,699,383 A	12-1997	Ichiyoshi, Osamu	375/297
*	Н	US-5,732,333 A	03-1998	Cox et al.	455/126
*	1	US-5,748,678 A	05-1998	Valentine et al.	375/297
*	J	US-5,760,646 A	05-1998	Belcher et al.	330/149
*	К	US-5,867,065 A	02-1999	Leyendecker, Robert Richard 330/	
*	L	US-5,892,397 A	04-1999	Belcher et al. 330/149	
*	М	US-5,913,172 A	06-1999	McCabe et al.	455/503

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		•			
	Р					,
	Q				·	
	R					
	S					
	Т					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Application/Control No.

10/533,860

Examiner

Jason M. Perilla

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Art Unit
Page 2 of 6

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,929,703 A	07-1999	Sehier et al.	330/149
*	В	US-5,920,808 A	07-1999	Jones et al.	455/127.1
*	С	US-5,923,712 A	07-1999	Leyendecker et al.	375/297
*	D	US-5,959,499 A	09-1999	Khan et al.	330/149
*	F	US-5,959,500 A	09-1999	Garrido, Armando Cova	330/151
*	F	US-6,043,707 A	03-2000	Budnik, Brian Joseph	330/10
*	G	US-6,075,411 A	06-2000	Briffa et al.	330/149
*	н	US-6,141,390 A	10-2000	Cova, Armando	375/297
*	ı	US-6,320,463 B1	11-2001	Leva et al.	330/149
*	J	US-2002/0016154 A1	02-2002	Huttunen, Mikko	455/63
*	к	US-6,369,648 B1	04-2002	Kirkman, George F.	330/43
*	L	US-6,396,350 B2	05-2002	Nam, Ki Y.	330/297
*	М	US-2002/0171485 A1	11-2002	Cova, Armando C.	330/149

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	·				
	0		·			
	Р				•	
1.50	Q				·	
	R					
	s					
	Т					

# NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Application/Control No.

10/533,860

Examiner

Jason M. Perilla

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Art Unit
2611

Page 3 of 6

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0035494 A1	02-2003	Bauder et al.	375/296
*	В	US-2003/0031270 A1	02-2003	Giardina et al.	375/296
*	С	US-2003/0072388 A1	04-2003	Francos et al.	375/296
*	D	US-2003/0063686 A1	04-2003	Giardina et al.	375/296
*	E	US-2003/0146787 A1	08-2003	Hedberg et al.	330/149
*	F	US-2003/0156657 A1	08-2003	Schrader et al.	375/295
*	G	U.S-2003/0156658 A1	08-2003	Dartois, Luc	375/297
*	Н	US-2003/0179830 A1	09-2003	Eidson et al.	375/296
*	1	US-2003/0197558 A1	10-2003	Bauder et al.	330/149
*	J	US-2003/0184374 A1	10-2003	Huang et al.	. 330/149
*	К	US-2003/0207680 A1	11-2003	Yang et al.	455/341
*	L	US-6,674,808 B1	01-2004	Griph et al.	375/285
*	М	US-6,680,649 B2	01-2004	Rydin, Arne	330/149

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	o					
	P		X 2			
	Q					
	R	·			·	
	s					
	Т			0		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
K	U	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited 10/533,860 TOUCHAIS ET Examiner Art Unit

Application/Control No.

10/533,860

Examiner

Jason M. Perilla

Applicant(s)/Patent Under Reexamination TOUCHAIS ET AL.

Art Unit
Page 4 of 6

#### **U.S. PATENT DOCUMENTS**

*		Document Number Date Country Code-Number-Kind Code MM-YYYY Name		Classification	
*	Α	US-2004/0028146 A1	02-2004	Winkler, Clive	375/260
*	В	US-2004/0057533 A1	03-2004	Kermalli, Munawar Hussein	375/296
*	С	US-6,731,168 B2	05-2004	Hedberg et al.	330/149
*	D	US-6,741,662 B1	05-2004	Francos et al.	375/297
*	Е	US-6,771,708 B1	08-2004	Suga et al.	375/278
*	F	US-6,853,246 B2	02-2005	Bauder et al.	330/149
*	G	US-2005/0032472 A1	02-2005	Jiang et al.	455/013.4
*	Н	US-6,885,241 B2	04-2005	Huang et al.	330/149
*	1	US-6,891,902 B2	05-2005	Talwar et al.	375/296
*	. J	US-2005/0163250 A1	07-2005	McCallister, Ronald Duane	375/296
*	К	US-2005/016325 A1	07-2005	McCallister, Ronald Duane 3	
*	L	US-2005/0169411 A1	08-2005	Kroeger, Brian William 375/35	
*	М	US-6,931,080 B2	08-2005	Giardina et al.	375/296

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р			·		
1 4	Q					-
	R					
	S			·		
	T					

# NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U			
	v			
	w			
	x			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Application/Control No. 10/533,860	Applicant(s)/Patent Under Reexamination TOUCHAIS ET AL.		
Examiner	Art Unit	•	
Jason M. Perilla	2611	Page 5 of 6	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,928,122 B2	08-2005	Opas et al.	375/296
*	В	US-2005/0231279 A1	10-2005	Moffatt et al.	330/149
*	С	US-6,985,704 B2	01-2006	Yang et al.	455/126
*	D	US-2006/0008028 A1	01-2006	Maltsev et al.	375/297
*	Ε	US-7,003,051 B2	02-2006	Francos et al.	375/296
*	F	US-2006/0039498 A1	02-2006	de Figueiredo et al.	. 375/297
*	G	US-7,016,431 B2	03-2006	Schrader et al.	375/296
*	Н	US-7,062,233 B2	08-2006	Huttunen, Mikko	455/114.3
*	1	US-7,099,399 B2	08-2006	McCallister, Ronald Duane	375/269
*	J	US-7,085,330 B1	08-2006	Shirali, Kedar	375/296
*	К	US-2006/0247898 A1	11-2006	Cha, Sung-Keun	702/188
*	L	US-7,289,773 B2	10-2007	Braithwaite, Richard Neil	455/91
*	М	US-7,295,815 B1	11-2007	Wright et al.	455/91

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					·
	Р		4. 24			
	Q					
	R		·			
	s	_				
	T .					

## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	υ		
	v		
	w		
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

#### Applicant(s)/Patent Under Application/Control No. Reexamination 10/533,860 TOUCHAIS ET AL. Notice of References Cited Art Unit Examiner Page 6 of 6 2611

# Jason M. Perilla

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,312,656 B2	12-2007	Saed, Aryan	330/149
	В	US-			
	С	US-		·	
	D	US-			
	E	US-		•	
	F	US-		·	
	G	US-			
	Н	US-			7
	1	US-			
	J	US-			
	К	US-			
- 5	L	US-			
٦	М	US-			

**U.S. PATENT DOCUMENTS** 

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					: /
	S			_		
	Т				•	

# NON-PATENT DOCUMENTS

		No. 1 ( No. 1
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	>	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.